

**COURSE DATA****Data Subject**

<b>Código</b>	44419
<b>Name</b>	Physical characterisation techniques
<b>Cycle</b>	Master's degree
<b>ECTS Credits</b>	4.5
<b>Curso académico</b>	2016 - 2017

**Study (s)**

<b>Degree</b>	<b>Center</b>	<b>Acad. year</b>	<b>Period</b>
2208 - M.U. en Nanociencia y Nanotecnología Molecular	FACULTY OF CHEMISTRY	1	First term

**Subject-matter**

<b>Degree</b>	<b>Subject-matter</b>	<b>Character</b>
2208 - M.U. en Nanociencia y Nanotecnología Molecular	3 - Physical characterisation techniques	Obligatory

**Coordination**

<b>Name</b>	<b>Department</b>
CORONADO MIRALLES, EUGENIO	320 - QUÍMICA INORGÁNICA

**SUMMARY****English version is not available**

Se pretende que los alumnos se familiaricen con las técnicas de caracterización física habitualmente utilizadas en nanociencia (técnicas de microscopia y espectroscopia) y en especial con las técnicas de caracterización y análisis de superficies.

**PREVIOUS KNOWLEDGE****Relationship to other subjects of the same degree**

There are no specified enrollment restrictions with other subjects of the curriculum.

**Other requirements**

There are no specified enrollment restrictions with other subjects of the curriculum.



## OUTCOMES

### 2208 - M.U. en Nanociencia y Nanotecnología Molecular

- Students can apply the knowledge acquired and their ability to solve problems in new or unfamiliar environments within broader (or multidisciplinary) contexts related to their field of study.
- Students are able to integrate knowledge and handle the complexity of formulating judgments based on information that, while being incomplete or limited, includes reflection on social and ethical responsibilities linked to the application of their knowledge and judgments.
- Students have the learning skills that will allow them to continue studying in a way that will be largely self-directed or autonomous.
- Students have the knowledge and understanding that provide a basis or an opportunity for originality in developing and/or applying ideas, often within a research context.
- To possess the necessary knowledge and abilities to continue with future studies in the PhD program in Nanoscience and Nanotechnology.
- For students from field of knowledge (e.g. chemistry) to be able to scientifically communicate and interact with colleagues from another field (e.g. physics) in the resolution of problems laid out by the Molecular Nanoscience and Nanotechnology.
- To acquire the basics knowledge in fundamentals, use and applications of microscopic and spectroscopic techniques used in nanotechnology.
- To know the technical and conceptual problems laid out by the physical properties measurement in single molecular systems (charge transport, optical properties, magnetic properties).

## LEARNING OUTCOMES

### English version is not available

Se pretende que los alumnos se familiaricen con las técnicas de caracterización física habitualmente utilizadas en nanociencia (técnicas de microscopia y espectroscopia) y en especial con las técnicas de caracterización y análisis de superficies.

## DESCRIPTION OF CONTENTS

### 1. Physical characterization techniques.



**CHAPTER 1: Far-field microscopies.**

- 1.1. Introduction
- 1.2. Optical microscopies
  - 1.2.1. Overview of geometrical optics
  - 1.2.2. Resolution limits and superresolution techniques: Aberrations and diffraction
- 1.3. Electron microscopies
  - 1.3.1. Fundamentals
  - 1.3.2. Instrumentation: electron sources and electrostatic lenses
  - 1.3.3. TEM, SEM y STEM
  - 1.3.4. Information that can be obtained from the different signals.

**CHAPTER 2: Optical spectroscopies.**

- 2.1. Optical properties of nanostructures: quantum confinement, excitons and plasmons.
- 2.2. Absorption and luminescence spectroscopies: energy gaps and the Frank-Condon principle.
- 2.3. Infrared and Raman spectroscopies: vibrations
- 2.4. Pump-probe spectroscopy: Excitation lifetimes.

**CHAPTER 3: Photoelectron spectroscopies.**

- 3.1. Photoelectric effect, work function, electron mean-free path and final state effects (screening).
- 3.2. Instrumentation: Light sources, monochromators, flood guns, energy analyzers
- 3.3. Instrumentation: Ultra-High Vacuum and sample preparation techniques in UHV
- 3.4. X-ray Photoelectron Spectroscopy (XPS): Chemical identification and Chemical shifts.
- 3.5. Ultraviolet Photoelectron Spectroscopy (UPS): Valence band, angle resolved UPS, band dispersion.
- 3.6. Synchrotron-based techniques: Near-Edge X-ray Absorption Fine Structure (NEXAFS) and magnetic dichroism.

**CHAPTER 4: Scanning probe microscopies.**

- 4.1. Scanning Tunneling Microscopy
  - 4.1.1. Theoretical foundations and instrumentation.
  - 4.1.2. Topographical and spectroscopic information with the STM
  - 4.1.3. Inelastic spectroscopy and elementary excitations
  - 4.1.4. STM manipulation
- 4.2. Atomic Force Microscopy
  - 4.2.1. Theoretical foundations and instrumentation
  - 4.2.2. Topography, friction and Force vs. Distance curves
  - 4.2.3. Mechanical properties of nanostructures
- 4.3. Other Scanning Probe Microscopies: Magnetic Force Microscopy (MFM) and Scanning Near-field Optical Microscopy (SNOM)

**WORKLOAD**

ACTIVITY	Hours	% To be attended
Theory classes	22.00	100
Seminars	7.00	100
Tutorials	6.00	100
Other activities	2.00	100
Preparation of evaluation activities	57.50	0
Preparing lectures	18.00	0
<b>TOTAL</b>	<b>112.50</b>	



## TEACHING METHODOLOGY

- Theory classes, participatory lectures
- Articles discussion.
- Chaired debate or discussion.
- Practical cases or seminar problems discussion.
- Seminars.
- Problems.
- Laboratory practices and demostracions and visit to installations.
- Experts conferences.
- Attendance to courses, conferences and round tables.

## EVALUATION

Written exam about the subject basic contents	70-90%
Attendance and active participation in seminars.	0-10%
Questions answering	10-20%

## REFERENCES

### Basic

- Practical Methods in Electron Microscopy. Ed. Glauer, A.M. Nort Holland Publishing Company. 1990-1997
- Desarrollo de técnicas de espectroscopía láser y su aplicación al análisis químico, Montero Catalina, Carlos, Universidad Complutense de Madrid, Servicio de Publicaciones, 2001.
- Introduction to Scanning Tunneling Microscopy. Chen, C.J. Oxford Scholarship Online. 2007.